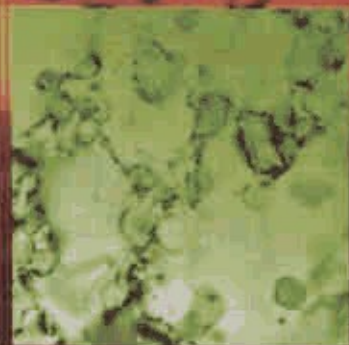


YANG LENG

MATERIALS CHARACTERIZATION

Introduction to Microscopic
and Spectroscopic Methods



 WILEY

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